

Application/Control No.	Applicant(s)/Patent under Reexamination
10/630,243	CHUEY, MARK D.
Examiner	Art Unit
Nam V. Nguyen	2635

SEARCHED				
Class	Subclass	Date	Examiner	
340	825.69	5/25/2005	NN	
340	825.79	5/25/2005	NN	
340	5.2+	5/25/2005	NN	
340	5.7+	5/25/2005	NN	
341	50	5/25/2005	NN	
341	176	5/25/2005	NN	
348	734	5/25/2005	NN	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Search East: USPAT; US-PUBS; EPO; JPO and Derwent.	5/25/2005	NN	
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